

AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

LISTING OF CLAIMS:

1. (Currently Amended) A reflector having a laminate structure of at least a high refractive index layer (A), a low refractive index layer (B), a metal layer (C) mainly composed of a metal selected from silver or aluminum, and a polymer base (D),

wherein the layer (A), the layer (B) and the layer (C) are laminated in the order of (A)/(B)/(C), and

wherein the polymer base (D) satisfies the following condition (I),

(I) the ~~ratio~~ content (Rn) of atoms of the same atoms elements as ~~atoms elements~~ (A2) (excluding metals) in atoms elements (A1) (excluding metals) relative to the ~~atoms elements~~ (A1) is not less than 98.0 atomic %, wherein the atoms elements (A1) are observed by the XPS measurement of portion at depths of 0 nm to 10 nm from a side of the reflective layer of the polymer base (D) and the atoms elements (A2) are observed by the XPS measurement of portion at depths of 50 nm to 10 μ m from a side of the reflective layer of the polymer base (D).

2. (Original) The reflector according to claim 1, wherein the polymer base (D) is a polymer film.

3. (Original) A lamp reflector using the reflector as described in claim 1.

4. (Original) A reflector under a light-guiding plate using the reflector as described in claim 1.
5. (Original) A backlight device using the reflector as described in claim 1.
6. (Original) A liquid crystal display using the reflector as described in claim 1.
7. (Currently Amended) A method for producing the reflector wherein a reflective layer having a laminate structure of a high refractive index layer (A), a low refractive index layer (B), and a metal layer (C) mainly composed of a metal selected from silver or aluminum is formed on a polymer base (D1) satisfying the following condition (II) in the order of (A)/(B)/(C),

(II) the ratio content (Rn_1) of atoms of the same ~~atoms~~ elements as ~~atoms~~ elements (A21) (excluding metals) in ~~atoms~~ elements (A11) (excluding metals) relative to the ~~atoms~~ elements (A11) is not less than 98.0 atomic %, wherein the ~~atoms~~ elements (A11) are observed by the XPS measurement of the surface forming a reflective layer of the polymer base (D1) and the ~~atoms~~ elements (A21) are observed by the XPS measurement of portion at depths of 50 nm to 10 μ m from a side of the reflective layer of the appropriate surface of the polymer base (D1).

8. (Original) The method for producing the reflector according to claim 7, wherein the polymer base (D1) is a polymer base (D2) in which a polymer base and a liquid are subjected to coming into contact with each other.